

ECE 538: VLSI System Testing

Assignment 4

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Duke Community Standard

By submitting this L^AT_EX document, I affirm that

1. I have adhered to the Duke Community Standard in completing this assignment.

Problem 1 Path Delay and Small Delay Defect Testing using Synopsys TetraMax:**a.****(i)**

Number of Critical Paths	50	100	150	200	250	300
Total Faults	50	100	150	200	250	300
Detected	44	82	123	128	129	128
Test Coverage	88.00%	82.00%	82.00%	64.00%	51.60%	42.67%
Patterns	9	18	19	19	19	18
CPU Time	0.02	0.02	0.03	0.02	0.03	0.05

Table 1: Results for path-delay faults, 0.15ns clock period